Sheet Resistance & Resistivity Measuring System

(Four Point Probe System)

This system, developed by the joint technical efforts of the “Korea Research Institute of Standards and Science” and the “Chang Min Co., Ltd.”, is indispensable in semiconductor manufacturing processes

Model CMT-SR2000N

Distributed by:

Materials Development Corporation

21541 Nordhoff Street, #B • Chatsworth, CA 91311

Tel: 818.700.8290 • Fax: 818.700.8304

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Feature

- Measures the sheet resistance & resistivity of Wafer, LCD, ITO, TFT, Thin film, etc.
- Measures for sheet resistance(ohm/sq) & resistivity (ohm-cm)
- Easy to use
- Multi - function

CHANCE MIN TECH CO.,

Specification

Measurement Range
1 mΩ /sq ~ 2 M/sq (V/I = 25 mΩ ~ 44.15 KΩ)

Operation
Operator simply places wafer on sample chuck and pushes the start button. Unit automatically ranges to correct range and display correct reading including decimal point and multiplier.

Probe Head
Convenient plug-in probe head/adapter assembly permits changing or replacing worn probe heads in minutes without special tools or alignment fixtures.
JANDEL probe heads are provided as standard equipment.

Direct Digital Display
Test results are displayed on direct LCD display.

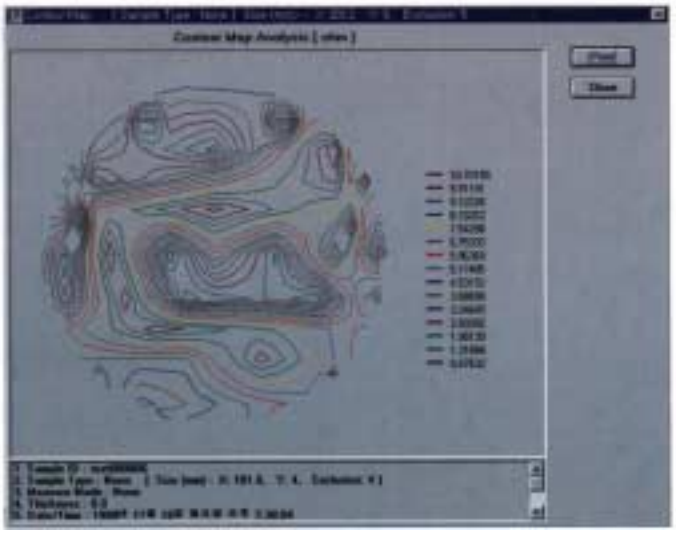
Measurement Time
Total test time less than 4 sec

Electronic Accuracy
0.5% for V/I of 5mΩ to 10KΩ at an ambient temperature of 20°C to 25°C

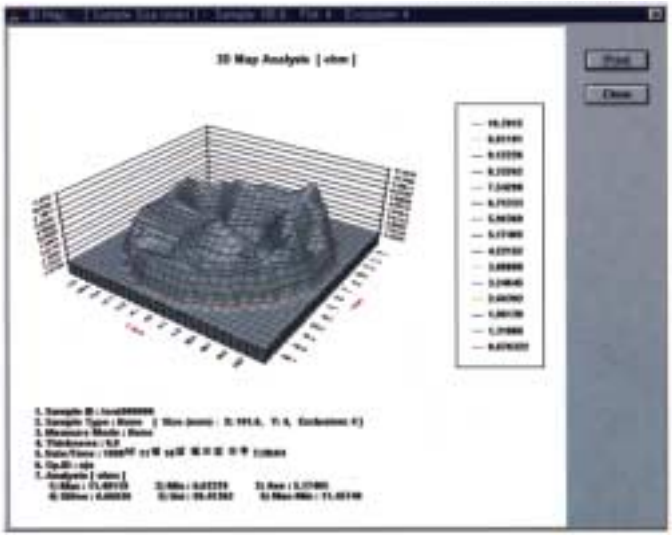
Jandel Four point probe Head

Maintenance & Service
The microprocessor based electronics employ state of the art component for trouble free operation and high reliability. All electronic components mounted on easily replaced printed boards.

Option
- Spare Probe head
- Full remote control (RS232C Interface) and Data analysis software. (Win 95/98)



Contour Map



3-Dimension Map

Manufacturer & Exporter

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